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Semiconductor devices - Part 16-7: Microwave integrated circuits - Attenuators

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 03/23

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**Semiconductor devices - Part 16-7: Microwave integrated
circuits - Attenuators
(IEC 60747-16-7:2022)**

Dispositifs à semiconducteurs - Partie 16-7: Circuits
intégrés hyperfréquences - Atténuateurs
(IEC 60747-16-7:2022)

Halbleiterbauelemente - Teil 16-7: Integrierte
Mikrowellenverstärker - Schaltdämpfer
(IEC 60747-16-7:2022)

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Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 60747-16-7:2023 (E)**European foreword**

The text of document 47E/794/FDIS, future edition 1 of IEC 60747-16-7, prepared by SC 47E "Discrete semiconductor devices" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60747-16-7:2023.

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In the official version, for Bibliography, the following notes have to be added for the standard indicated:

- IEC 60747-16-1:2001 NOTE Harmonized as EN 60747-16-1:2002 (not modified)
- IEC 60747-16-1:2001/AMD1:2007 NOTE Harmonized as EN 60747-16-1:2002/A1:2007 (not modified)
- IEC 60747-16-1:2001/AMD2:2017 NOTE Harmonized as EN 60747-16-1:2002/A2:2017 (not modified)
- IEC 60747-16-4:2004 NOTE Harmonized as EN 60747-16-4:2004 (not modified)
- IEC 60747-16-4:2004/AMD1:2009 NOTE Harmonized as EN 60747-16-4:2004/A1:2011 (not modified)
- IEC 60747-16-4:2004/AMD2:2017 NOTE Harmonized as EN 60747-16-4:2004/A2:2017 (not modified)
- IEC 60747-16-6:2019 NOTE Harmonized as EN IEC 60747-16-6:2019 (not modified)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

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NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60747-1	2006	Semiconductor devices - Part 1: General	-	-
+ A1	2010		-	-
IEC 60747-4	-	Semiconductor devices - Discrete devices -- Part 4: Microwave diodes and transistors		-
IEC 61340-5-1	-	Electrostatics - Part 5-1: Protection of electronic devices from electrostatic phenomena - General requirements	EN 61340-5-1	-
IEC/TR 61340-5-2	-	Electrostatics - Part 5-2: Protection of electronic devices from electrostatic phenomena - User guide	-	-



IEC 60747-16-7

Edition 1.0 2022-11

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices –
Part 16-7: Microwave integrated circuits – Attenuators**

**Dispositifs à semiconducteurs –
Partie 16-7: Circuits intégrés hyperfréquences – Atténuateurs**





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Edition 1.0 2022-11

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices –
Part 16-7: Microwave integrated circuits – Attenuators**

**Dispositifs à semiconducteurs –
Partie 16-7: Circuits intégrés hyperfréquences – Atténuateurs**

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SEMICONDUCTOR DEVICES –

**Part 16-7: Microwave integrated circuits –
Attenuators**

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The text of this International Standard is based on the following documents:

Draft	Report on voting
47E/794/FDIS	47E/798/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

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- reconfirmed,
- withdrawn,
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SEMICONDUCTOR DEVICES –

Part 16-7: Microwave integrated circuits – Attenuators

1 Scope

This part of IEC 60747 specifies the terminology, essential ratings and characteristics, and measuring methods of microwave integrated circuit attenuators.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60747-1:2006, *Semiconductor devices – Part 1: General*
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IEC 60747-4, *Semiconductor devices – Discrete devices – Part 4: Microwave diodes and transistors*

IEC 61340-5-1, *Electrostatics – Part 5-1: Protection of electronic devices from electrostatic phenomena – General requirements*

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